

Notice of References Cited	Application/Control No. 09/910,371	Applicant(s)/Patent Under Reexamination SEEM, JOHN E.	
	Examiner Jeffrey R. West	Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,990,893	02-1991	Kiluk, Czeslaw	340/573.1
*	B	US-5,555,195	09-1996	Jensen et al.	700/276
	C	US-4,701,698	10-1987	Karlsson et al.	324/116
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-08304120-A	11-1996	JP	Furuta	G01D9/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Carey et al., "Resistant and Test-Based Outlier Rejection: Effects on Gaussian One- and Two-Sample Inference". Technometrics, Vol. 39, No. 3. 1999.
*	V	Sematech, "The Engineers Statistics Internet (ESI) Handbook: Grubbs' Test for Outliers." 1999.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.